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- *EPIC*TM (Enhanced-Performance Implanted CMOS) Submicron Process
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- Typical V_{OLP} (Output Ground Bounce)
 < 0.8 V at V_{CC} = 3.3 V, T_A = 25°C
- Typical V_{OHV} (Output V_{OH} Undershoot)
 > 2 V at V_{CC} = 3.3 V, T_A = 25°C
- Inputs Accept Voltages to 5.5 V
- Package Options Include Plastic Small-Outline (D), Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages, Ceramic Chip Carriers (FK) and Flat (W) Package, and DIPs (J)

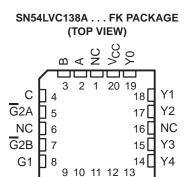
description

The SN54LVC138A 3-line to 8-line decoder/demultiplexer is designed for 2.7-V to 3.6-V V_{CC} operation and the SN74LVC138A 3-line to 8-line decoder/demultiplexer is designed for 1.65-V to 3.6-V V_{CC} operation.

The 'LVC138A devices are designed for highperformance memory-decoding or data-routing applications requiring very short propagation

01104210100			TAORAOL							
SN74LVC138A D, DB, OR PW PACKAGE										
(TOP VIEW)										
_	\Box	\neg								
AL	1	16	V _{CC}							
B	2	15	Y0							
с [3	14	Y1							
G2A	4	13	Y2							
G2B	5	12	Y3							
G1 [6	11	Y4							
Y7 [7	10	Y5							
GND [8	9	Y6							
٦										

SN54LVC138A ... J OR W PACKAGE



NC - No internal connection

DND

Υ5

delay times. In high-performance memory systems, these decoders minimize the effects of system decoding. When employed with high-speed memories utilizing a fast enable circuit, the delay times of these decoders and the enable time of the memory are usually less than the typical access time of the memory. This means that the effective system delay introduced by the decoders is negligible.

The conditions at the binary-select inputs and the three enable inputs select one of eight output lines. Two active-low enable inputs and one active-high enable input reduce the need for external gates or inverters when expanding. A 24-line decoder can be implemented without external inverters and a 32-line decoder requires only one inverter. An enable input can be used as a data input for demultiplexing applications.

Inputs can be driven from either 3.3-V or 5-V devices. This feature allows the use of these devices as translators in a mixed 3.3-V/5-V system environment.

The SN54LVC138A is characterized for operation over the full military temperature range of -55° C to 125° C. The SN74LVC138A is characterized for operation from -40° C to 85° C.



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PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas instruments standard warranty. Production processing does not necessarily include testing of all parameters.

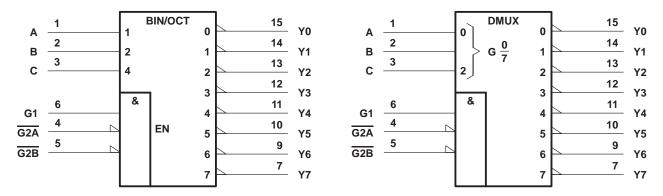


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	FUNCTION TABLE												
ENA	BLE INP	PUTS	SEL	ECT INP	UTS				OUTI	PUTS			
G1	G2A	G2B	С	В	Α	Y0	Y1	Y2	Y3	Y4	Y5	Y6	Y7
Х	Н	Х	Х	Х	Х	н	Н	Н	Н	Н	Н	Н	Н
X	Х	н	Х	Х	Х	н	Н	Н	Н	Н	Н	Н	Н
L	Х	Х	Х	Х	Х	н	Н	Н	Н	Н	Н	Н	Н
н	L	L	L	L	L	L	Н	Н	Н	Н	Н	Н	Н
н	L	L	L	L	Н	н	L	Н	Н	Н	Н	Н	Н
н	L	L	L	Н	L	н	Н	L	Н	Н	Н	Н	Н
н	L	L	L	Н	Н	н	Н	Н	L	Н	Н	Н	Н
н	L	L	н	L	L	н	Н	Н	н	L	Н	Н	Н
н	L	L	н	L	Н	н	Н	Н	Н	Н	L	Н	Н
н	L	L	н	Н	L	н	Н	Н	Н	Н	Н	L	Н
н	L	L	н	Н	Н	н	Н	Н	Н	Н	Н	Н	L

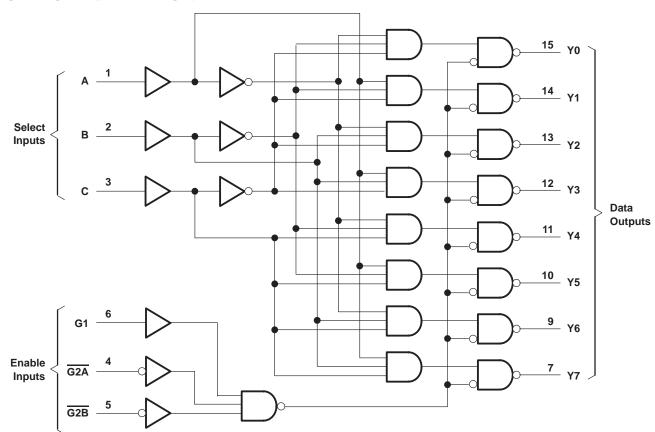
logic symbols (alternatives)[†]



[†] These symbols are in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, DB, J, PW, and W packages.



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logic diagram (positive logic)

Pin numbers shown are for the D, DB, J, PW, and W packages.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage range, V _{CC}		
Input voltage range, V _I (see Note 1)		
Output voltage range, V _O (see Notes 1 and 2)		-0.5 V to V _{CC} + 0.5 V
Input clamp current, I _{IK} (V _I < 0)		–50 mA
Output clamp current, I _{OK} (V _O < 0)		–50 mA
Continuous output current, IO		±50 mA
Continuous current through V _{CC} or GND		±100 mA
Package thermal impedance, θ_{JA} (see Note 3):	Dpackage	113°C/W
	DB package	131°C/W
	PW package	149°C/W
Storage temperature range, T _{stg}		–65°C to 150°C

† Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. The input negative-voltage and output voltage ratings may be exceeded if the input and output current ratings are observed.

- 2. The value of V_{CC} is provided in the recommended operating conditions table.
- 3. The package thermal impedance is calculated in accordance with JESD 51.



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recommended operating conditions (see Note 4)

			SN54L	/C138A	SN74L	/C138A	
			MIN	MAX	MIN	MAX	UNIT
	Cumple weltere	Operating	2	3.6	1.65	3.6	v
VCC	Supply voltage	Data retention only	1.5		1.5		v
		V _{CC} = 1.65 V to 1.95 V			$0.65 \times V_{CC}$		
VIH	High-level input voltage	$V_{CC} = 2.3 \text{ V to } 2.7 \text{ V}$			1.7		V
		$V_{CC} = 2.7 \text{ V to } 3.6 \text{ V}$	2		2		
		V _{CC} = 1.65 V to 1.95 V				$0.35 \times V_{CC}$	
VIL	Low-level input voltage	V_{CC} = 2.3 V to 2.7 V				0.7	V
		V _{CC} = 2.7 V to 3.6 V		0.8		0.8	
VI	Input voltage		0	5.5	0	5.5	V
VO	Output voltage		0	VCC	0	VCC	V
		V _{CC} = 1.65 V				-4	
lau		$V_{CC} = 2.3 V$				-8	mA
ЮН	High-level output current	$V_{CC} = 2.7 V$		-12		-12	IIIA
		$V_{CC} = 3 V$		-24		-24	
		V _{CC} = 1.65 V				4	
la.	l our lovel output ourrest	V _{CC} = 2.3 V				8	mA
IOL	Low-level output current	V _{CC} = 2.7 V		12		12	mA
		$V_{CC} = 3 V$		24		24	
$\Delta t / \Delta v$	Input transition rise or fall rate		0	10	0	10	ns/V
Тд	Operating free-air temperature		-55	125	-40	85	°C

NOTE 4: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



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DADAMETED	TEST CONDITIONS		SN54	LVC138	4	SN74	LVC138	4	UNIT
PARAMETER	TEST CONDITIONS	Vcc	MIN	TYP†	MAX	MIN	TYP†	MAX	UNIT
	1	1.65 V to 3.6 V				V _{CC} -0.2			
	I _{OH} = -100 μA	2.7 V to 3.6 V	V _{CC} -0.2	2					
	$I_{OH} = -4 \text{ mA}$	1.65 V				1.2			
Vон	I _{OH} = -8 mA	2.3 V				1.7			V
	12	2.7 V	2.2			2.2			
	I _{OH} = -12 mA	3 V	2.4			2.4			
	I _{OH} = -24 mA	3 V	2.2			2.2			
	I _{OL} = 100 μA	1.65 V to 3.6 V						0.2	
		2.7 V to 3.6 V			0.2				
\/	I _{OL} = 4 mA	1.65 V						0.45	V
VOL	I _{OL} = 8 mA	2.3 V						0.7	v
	I _{OL} = 12 mA	2.7 V			0.4			0.4	
	I _{OL} = 24 mA	3 V			0.55			0.55	
lj	$V_{I} = 5.5 V \text{ or GND}$	3.6 V			±5			±5	μA
ICC	$V_{I} = V_{CC} \text{ or } GND, \qquad I_{O} = 0$	3.6 V			10			10	μA
ΔICC	One input at V_{CC} – 0.6 V, Other inputs at V_{CC} or GND	2.7 V to 3.6 V			500			500	μA
Ci	$V_{I} = V_{CC}$ or GND	3.3 V		5			5		pF

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

[†] All typical values are at $V_{CC} = 3.3 \text{ V}$, $T_A = 25^{\circ}\text{C}$.

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figure 3)

PARAMETER	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 2.7 V		V _{CC} = 3.3 V ± 0.3 V		UNIT
			MIN	MAX	MIN	MAX	
	A or B or C			7.9	1	6.7	
^t pd	G2A or G2B	Y		7.4	1	6.5	ns
	G1			6.4	1	5.8	

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figures 1 through 3)

PARAMETER			SN74LVC138A							
	FROM (INPUT)	TO (OUTPUT)	V _{CC} = 1.8 V V _{CC} = 2.5 V ± 0.2 V V _{CC} =		$V_{CC} = 1.8 V$ $V_{CC} = 2.5 V$ $V_{CC} = 2.7 V$ $V_{CC} = 2.7 V$ $V_{CC} = 2.7 V$		V _{CC} = 3.3 V ± 0.3 V		UNIT	
			TYP	MIN	MAX	MIN	MAX	MIN	MAX	
	A or B or C	Y	15.9	1	9.9		7.9	1	6.7	ns
t _{pd}	G2A or G2B		15.4	1	9.4		7.4	1	6.5	
	G1		14.4	1	8.4		6.4	1	5.8	
^t sk(o) [‡]									1	ns

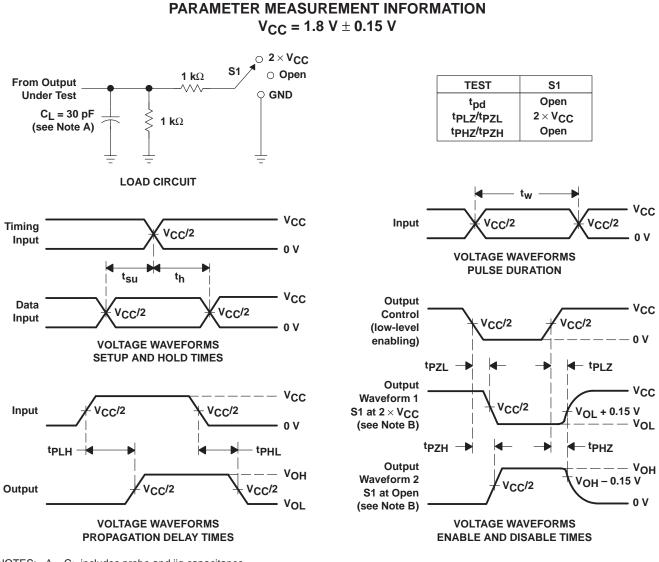
[‡] Skew between any two outputs of the same package switching in the same direction



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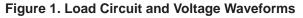
operating characteristics, T_A = 25°C

PARAMETER		TEST	V _{CC} = 1.8 V	$V_{CC} = 2.5 V$	V _{CC} = 3.3 V	UNIT
	FARAMETER	CONDITIONS	ТҮР	TYP	TYP	UNIT
Cpd	Power dissipation capacitance	f = 10 MHz	25	26	27	pF



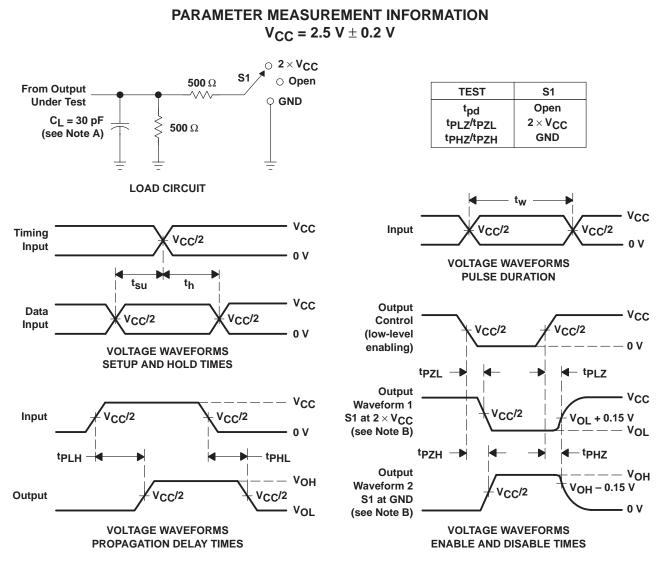
NOTES: A. CL includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control. C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , t_f \leq 2 ns, t_f \leq 2 ns.
- D. The outputs are measured one at a time with one transition per measurement.
- E. tPLZ and tPHZ are the same as tdis.
- F. tpzL and tpzH are the same as ten.
- G. tPLH and tPHL are the same as tpd.





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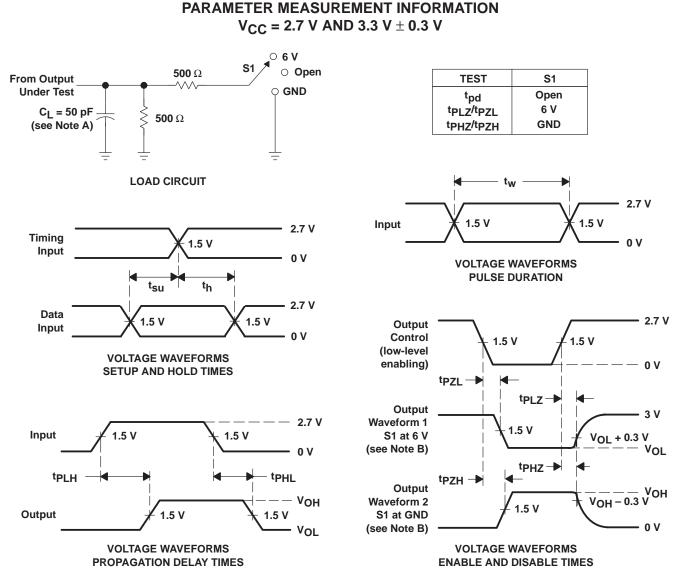
- NOTES: A. CI includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control. C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , t_f \leq 2 ns, t_f \leq 2 ns.
 - D. The outputs are measured one at a time with one transition per measurement.

 - E. tPLZ and tPHZ are the same as tdis.
 - F. tpzL and tpzH are the same as ten.
 - G. tpl H and tpHI are the same as tpd.

Figure 2. Load Circuit and Voltage Waveforms



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NOTES: A. CL includes probe and jig capacitance.

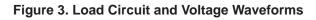
B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.

- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 10 MHz, Z_O = 50 Ω , t_f \leq 2.5 ns, t_f \leq 2.5 ns.
- D. The outputs are measured one at a time with one transition per measurement.

E. t_{PLZ} and t_{PHZ} are the same as t_{dis} .

F. t_{PZL} and t_{PZH} are the same as t_{en}.

G. tPLH and tPHL are the same as tpd.





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